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3 Degradation of the characteristics of p/sup +/ poly MOS capacitors with N nitrided gate oxide due to post nitrogen annealing

Mazumder, M.K.; Teramoto, A.; Kobayashi, K.; Sekine, M.; Kawazu, S.; Koyama, H. Integrated Reliability Workshop Final Report, 1997 IEEE International, 1997 Page(s): 142 -143

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4 Effects of water vap r anneal on MIS devices made of nitrided gate dielectrics

Xiewen Wang; Khare, M.; Ma, T.P.

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Guckel, H.; Sniegowski, J.J.; Christenson, T.R. Micro Electro Mechanical Systems, 1989, Proceedings, An Investigation of Micro Structures, Sensors, Actuators, Machines and Robots. IEEE, 1989

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O- By Author	Chung, G.Y.; Tin, C.C.; Williams, J.R.; McDonald, K.; Chanana, R.K.; Weller, R.A.; Pantelides, S.T.; Feldman, L.C.; Holland, O.W.; Das, M.K.; Palmour, J.W.
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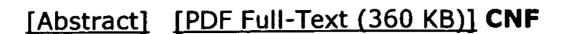
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